



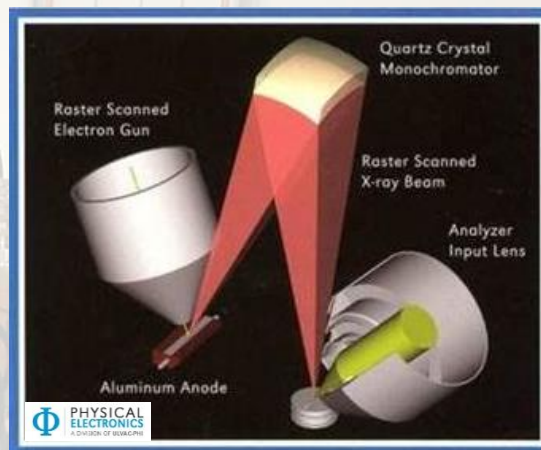
Enhance your research capabilities with the PHI Versaprobe II X-ray Photoelectron Spectrometer

Multi-Technique Scanning XPS Microprobe

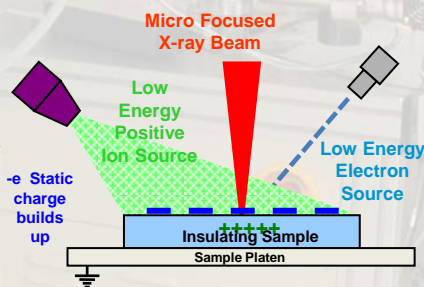
- High sensitivity micro-area chemical state analysis
- High performance sputter depth profiling
- Equipped with Ultraviolet Photoelectron Spectroscopy
- Temperature stage capabilities
- High productivity and ease-of-use

Applications

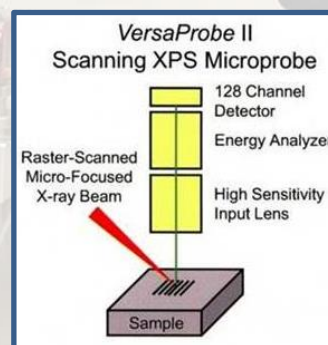
- Organic and inorganic chemistry and advanced materials research
- Surface chemistry, corrosion, catalysis, and adhesion
- Thin film characterization
- Medical device characterization
- Tribology, material and lubricant transfer characterization
- Magnetic storage media and complex multilayer structures
- Semiconductor and photovoltaic processes



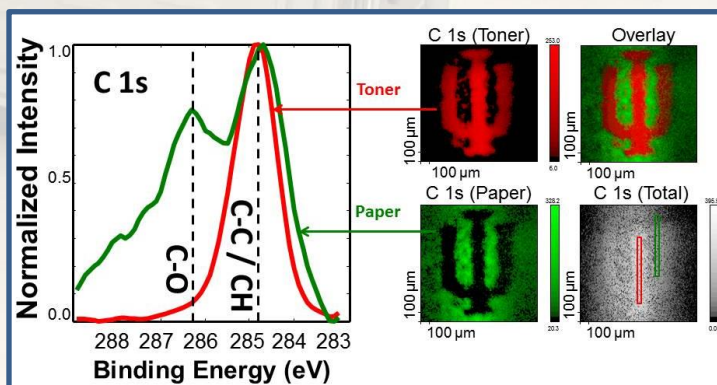
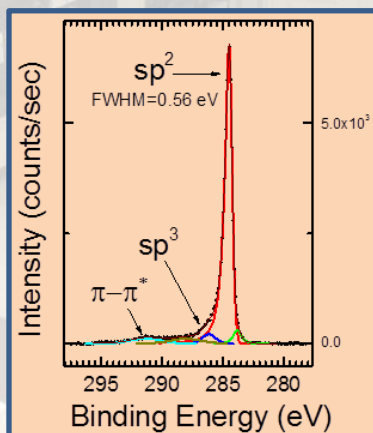
Dual Beam Charge Neutralization



Elemental Chemical Mapping



HOPG C 1s High Resolution



Contact Yaroslav Losovyj
(ylozovyy@indiana.edu) to discuss your XPS needs
<http://nano.indiana.edu/XPS.html>